

General Description

FSMOS[®] MOSFET is based on Oriental Semiconductor's unique device design to achieve low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. The low V_{th} series is specially optimized for synchronous rectification systems with low driving voltage.

Features

- Low $R_{DS(ON)}$ & FOM
- Extremely low switching loss
- Excellent reliability and uniformity
- Fast switching and soft recovery



Applications

- Switching mode power supply
- Motor driver
- Battery protection
- DC-DC convertor
- Inverter
- UPS

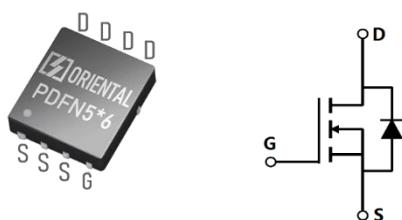
Key Performance Parameters

Parameter	Value	Unit
V_{DS}	80	V
I_D , pulse	520	A
$R_{DS(ON)}$, max @ $V_{GS}=10V$	2.4	mΩ
Q_g	73.8	nC

Marking Information

Product Name	Package	Marking
SFS08R024UGF	PDFN5x6	SFS08R024UG

Package & Pin information



Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	80	V
Gate-source voltage	V_{GS}	± 20	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	130	A
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	$I_{D,\text{pulse}}$	520	A
Continuous diode forward current ¹⁾ , $T_C=25^\circ\text{C}$	I_S	130	A
Diode pulsed current ²⁾ , $T_C=25^\circ\text{C}$	$I_{S,\text{pulse}}$	520	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	132	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	205	mJ
Operation and storage temperature	T_{stg}, T_j	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\theta JC}$	1.14	$^\circ\text{C}/\text{W}$
Thermal resistance, junction-ambient ⁴⁾	$R_{\theta JA}$	62	$^\circ\text{C}/\text{W}$

Electrical Characteristics at $T_j=25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	80			V	$V_{GS}=0 \text{ V}, I_D=250 \mu\text{A}$
Gate threshold voltage	$V_{GS(\text{th})}$	1		2.5	V	$V_{DS}=V_{GS}, I_D=250 \mu\text{A}$
Drain-source on-state resistance	$R_{DS(\text{ON})}$		2	2.4	$\text{m}\Omega$	$V_{GS}=10 \text{ V}, I_D=50 \text{ A}$
			2.7	3.5		$V_{GS}=4.5 \text{ V}, I_D=50 \text{ A}$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=20 \text{ V}$
				-100		$V_{GS}=-20 \text{ V}$
Drain-source leakage current	I_{DSS}			1	μA	$V_{DS}=80 \text{ V}, V_{GS}=0 \text{ V}$
Gate resistance	R_G		2.8		Ω	$f=1 \text{ MHz}, \text{Open drain}$

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C _{iss}		4850		pF	V _{GS} =0 V, V _{DS} =25 V, f=100 kHz
Output capacitance	C _{oss}		1950		pF	
Reverse transfer capacitance	C _{rss}		116		pF	
Turn-on delay time	t _{d(on)}		13		ns	V _{GS} =10 V, V _{DS} =40 V, R _G =2 Ω, I _D =40 A
Rise time	t _r		11		ns	
Turn-off delay time	t _{d(off)}		59		ns	
Fall time	t _f		22		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q _g		73.8		nC	V _{GS} =10 V, V _{DS} =40 V, I _D =40 A
Gate-source charge	Q _{gs}		12.4		nC	
Gate-drain charge	Q _{gd}		12		nC	
Gate plateau voltage	V _{plateau}		3		V	

Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V _{SD}			1.3	V	I _s =12 A, V _{GS} =0 V
Reverse recovery time	t _{rr}		70		ns	V _R =40 V, I _s =40 A, di/dt=100 A/μs
Reverse recovery charge	Q _{rr}		66		nC	
Peak reverse recovery current	I _{rrm}		1.6		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R_{θJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_a=25 °C.
- 5) V_{DD}=50 V, V_{GS}=10 V, L=0.3 mH, starting T_j=25 °C.

Electrical Characteristics Diagrams

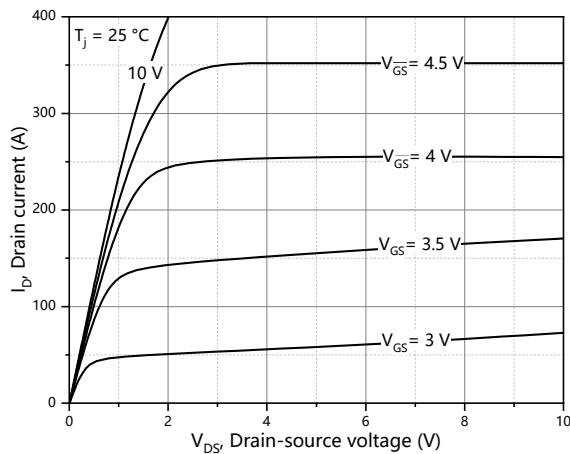


Figure 1. Typ. output characteristics

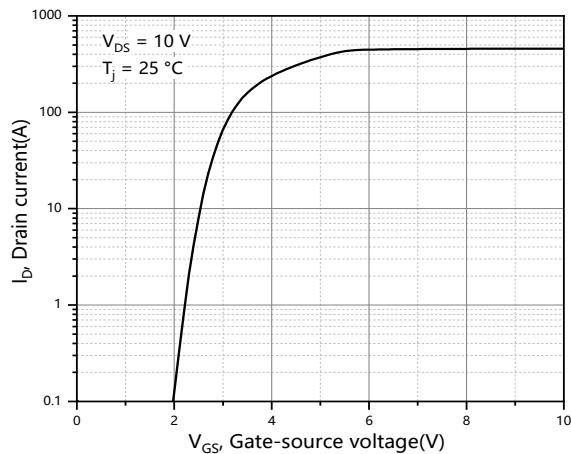


Figure 2. Typ. transfer characteristics

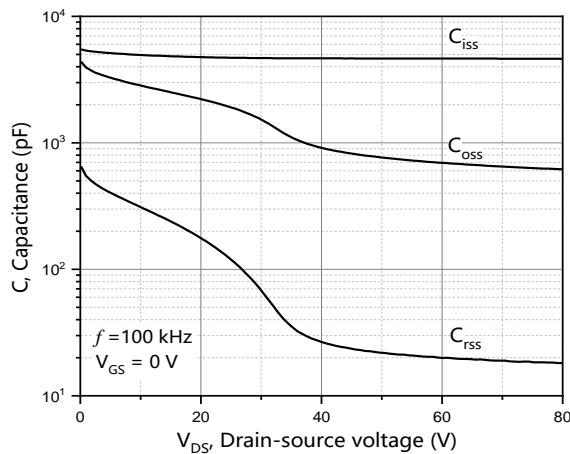


Figure 3. Typ. capacitances

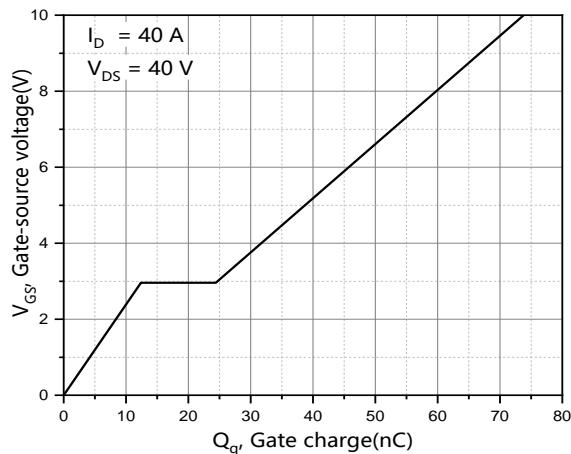


Figure 4. Typ. gate charge

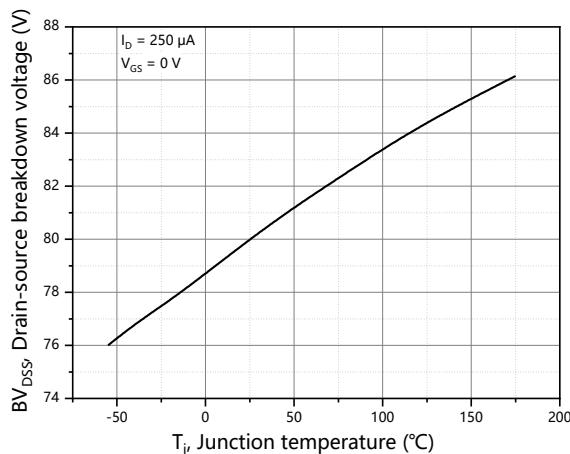


Figure 5. Drain-source breakdown voltage

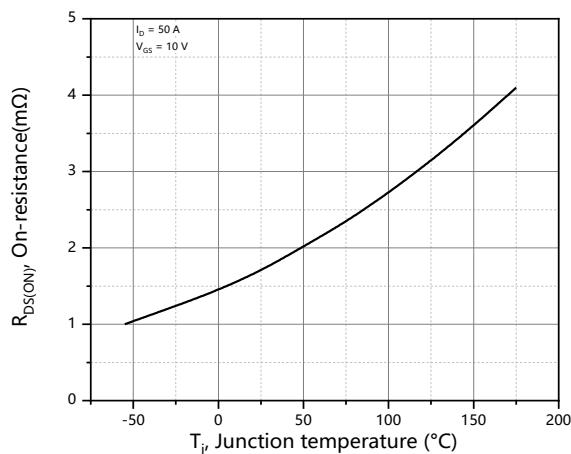
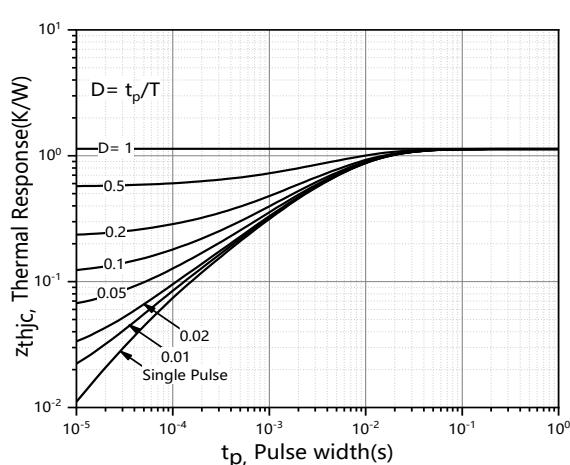
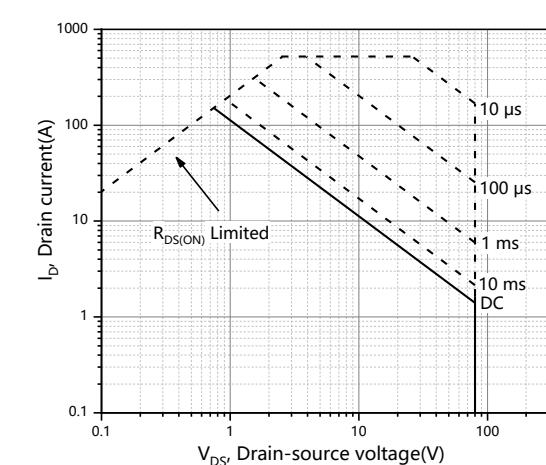
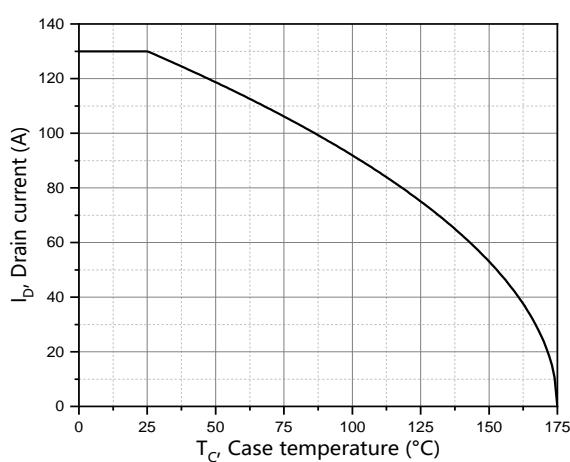
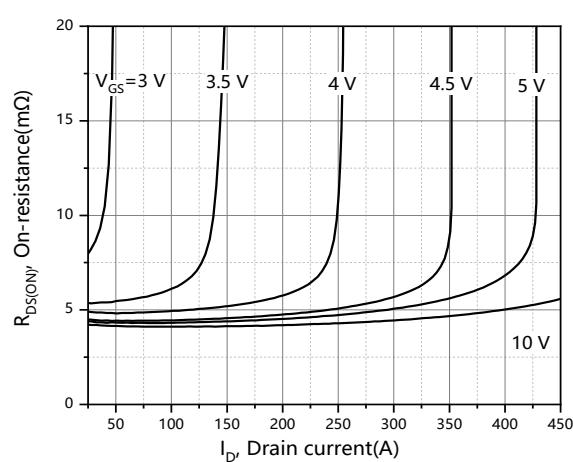
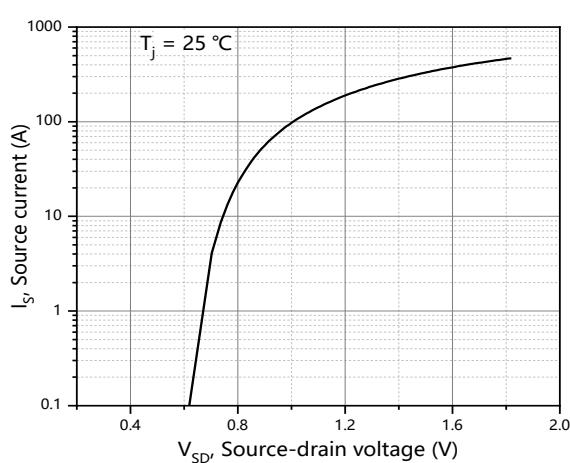
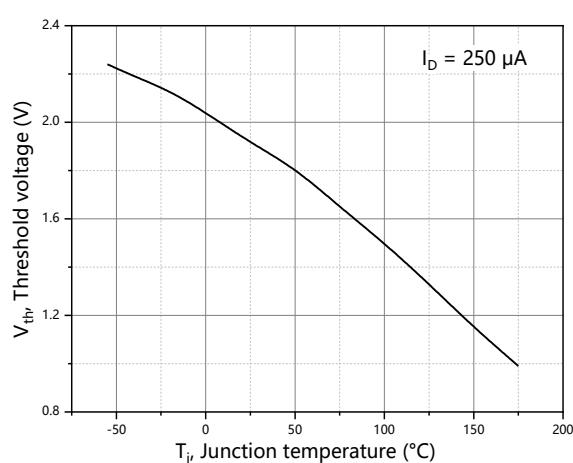


Figure 6. Drain-source on-state resistance



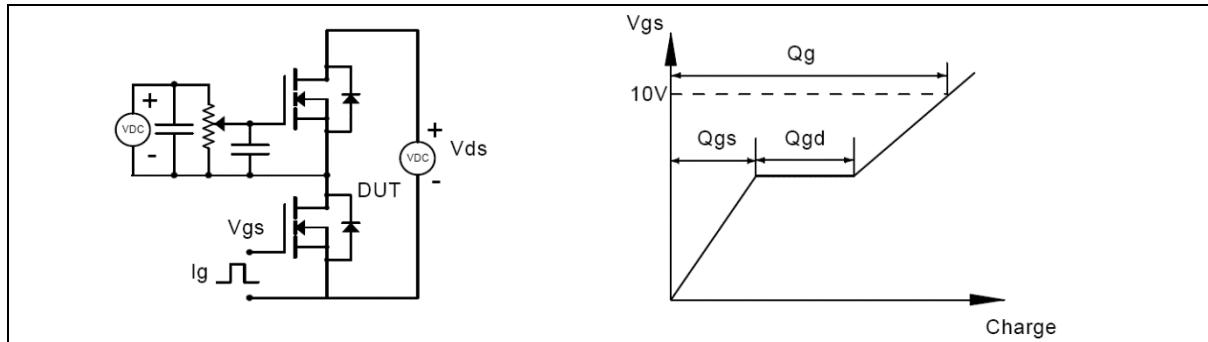


Figure 1. Gate charge test circuit & waveform

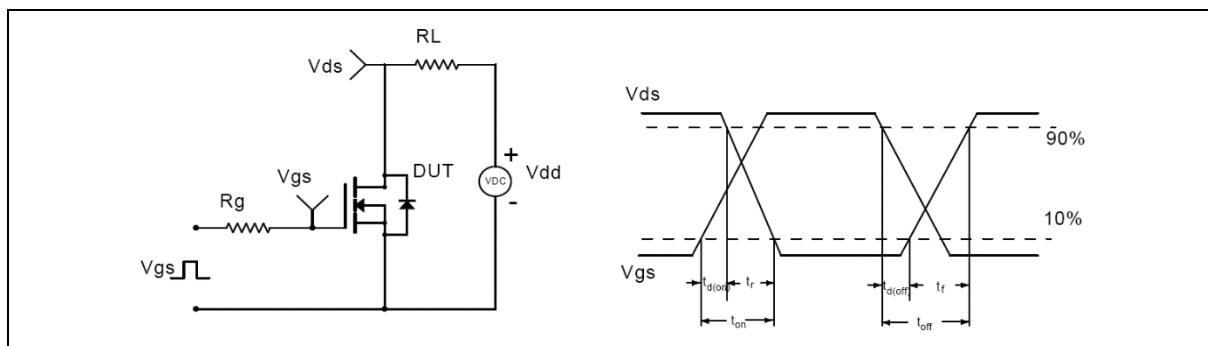


Figure 2. Switching time test circuit & waveforms

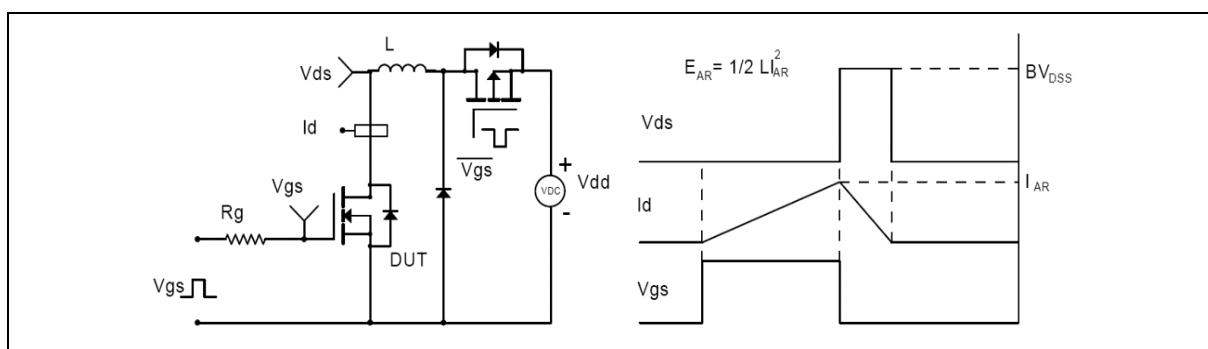


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

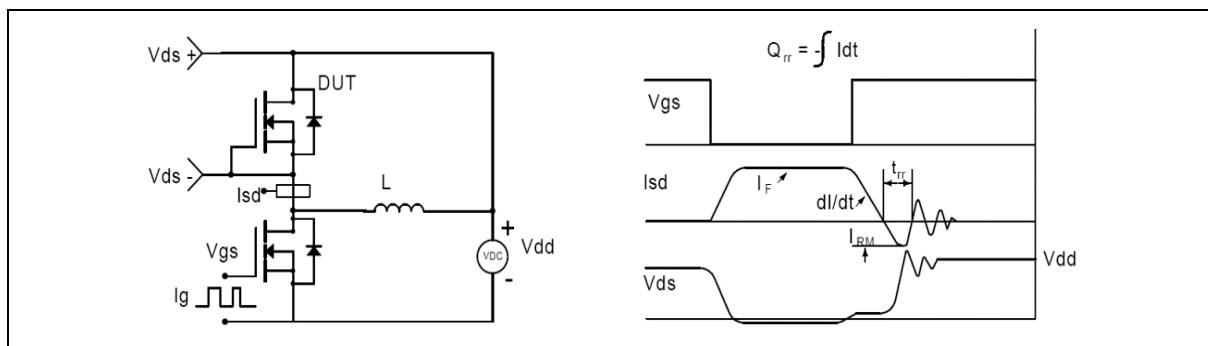
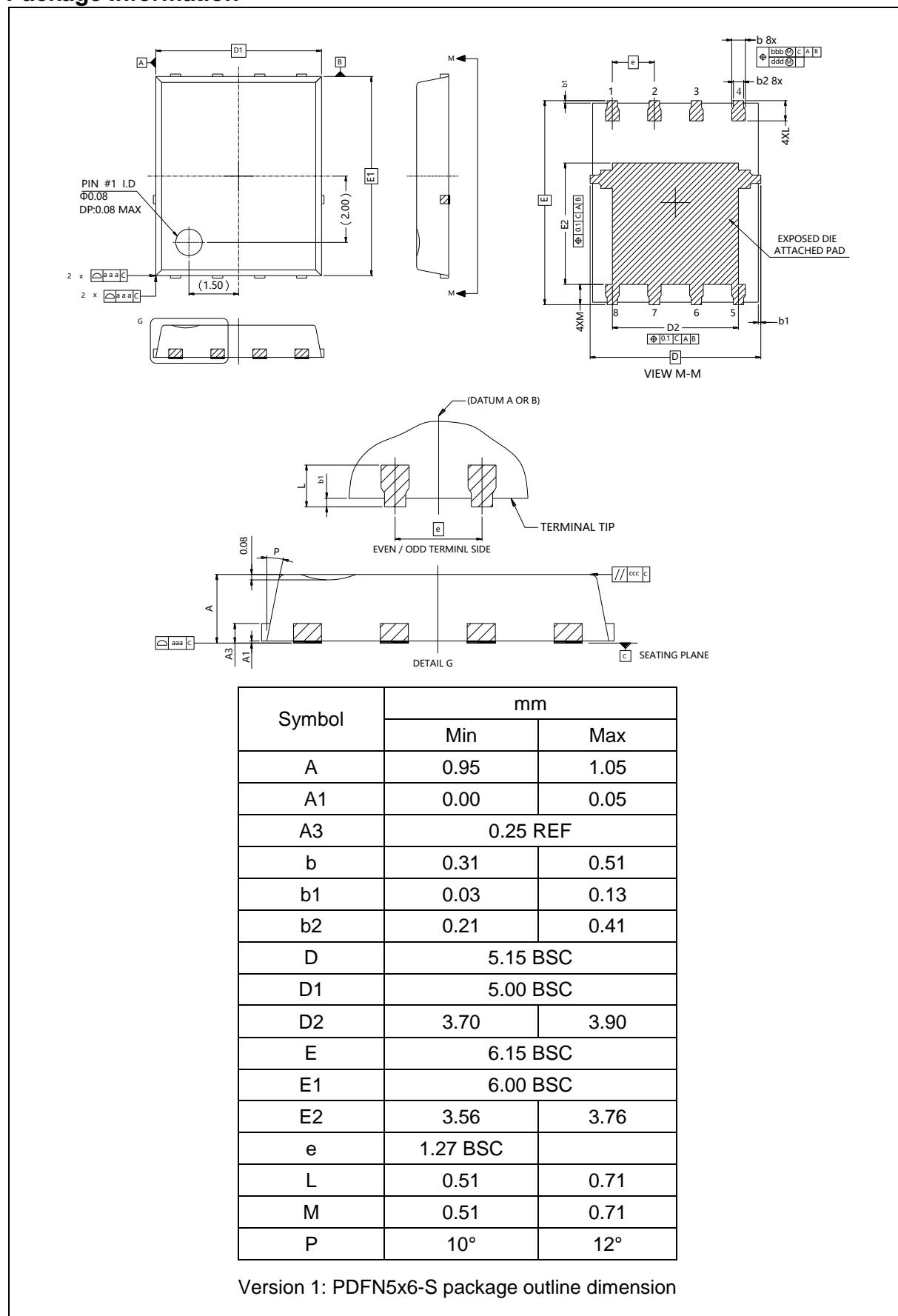


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information



Ordering Information

Package Type	Units/Reel	Reels/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
PDFN5x6-S	5000	1	5000	10	50000

Product Information

Product	Package	Pb Free	RoHS	Halogen Free
SFS08R024UGF	PDFN5x6	yes	yes	yes

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